



# 2.5V TO 3.3V HIGH PERFORMANCE CLOCK BUFFER

IDT5V2310

## FEATURES:

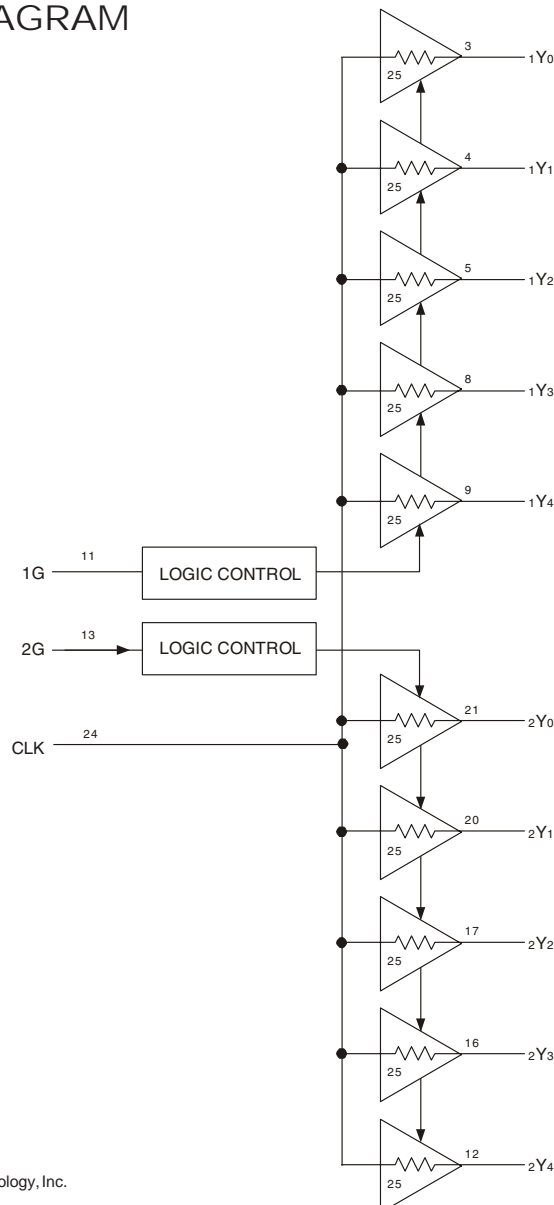
- High performance 1:10 clock driver for general purpose applications
- Operates up to 200MHz at  $V_{DD} = 3.3V$
- Pin-to-pin skew < 100ps
- $V_{DD}$  range: 2.3V to 3.6V
- Output enable glitch suppression
- Distributes one clock input to two banks of five outputs
- 25Ω on-chip series dampening resistors
- Available in TSSOP and VFQFPN packages

## DESCRIPTION:

The IDT5V2310 is a high performance, low skew clock buffer that operates up to 200MHz. Two banks of five outputs each provide low skew copies of CLK. Through the use of control pins 1G and 2G, the outputs of banks 1Y(0:4) and 2Y(0:4) can be placed in a low state regardless of CLK input. The device operates in 2.5V and 3.3V environments. The built-in output enable glitch suppression ensures a synchronized output enable sequence to distribute full period clock signals.

The IDT5V2310 is characterized for operation from -40°C to +85°C.

## FUNCTIONAL BLOCK DIAGRAM

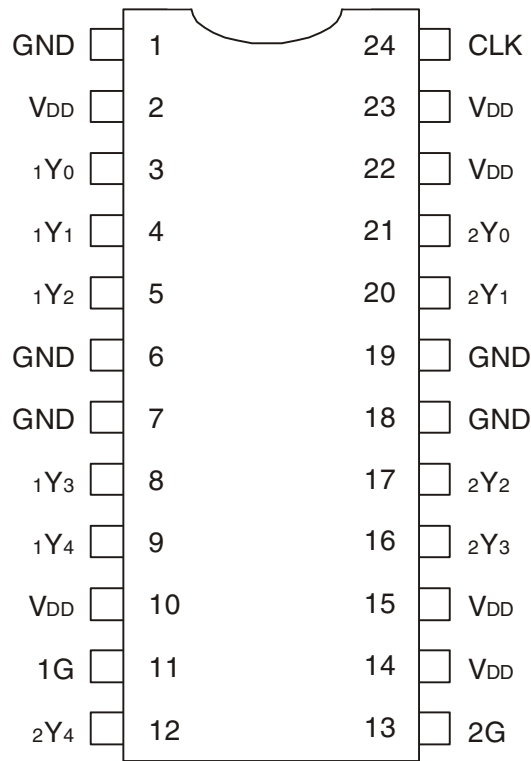


The IDT logo is a registered trademark of Integrated Device Technology, Inc.

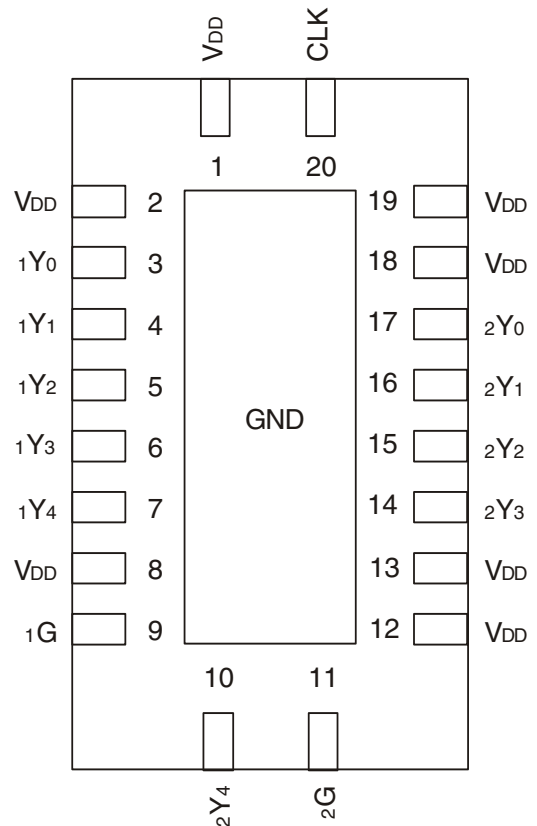
INDUSTRIAL TEMPERATURE RANGE

MAY 2010

PIN CONFIGURATION



TSSOP  
TOP VIEW



VFQFPN  
TOP VIEW

ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Description	Max	Unit
VDD	Power Supply Voltage	-0.5 to +4.6	V
Vi	Input Voltage <sup>(2)</sup>	-0.5 to VDD +0.5	V
Vo	Output Voltage <sup>(2)</sup>	-0.5 to VDD +0.5	V
IiK	Input Clamp Current Vi < 0 or Vi > VDD	±50	mA
IoK	Output Clamp Current Vo < 0 or Vo > VDD	±50	mA
Io	Continuous Total Output Current Vo < 0 to VDD	±50	mA
TSTG	Storage Temperature	-65 to +150	°C

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- Not to exceed 4.6V.

CAPACITANCE (TA = +25°C, f = 1MHz, VIN = 0V)

Parameter	Description	Min.	Typ.	Max.	Unit
CIN	Input Capacitance Vi = 0V or VDD	—	2.5	—	pF

FUNCTION TABLE<sup>(1)</sup>

Inputs			Outputs	
1G	2G	CLK	1Y(0:4)	2Y(0:4)
L	L	X	L	L
H	L	H	H	L
L	H	H	L	H
H	H	H	H	H

NOTE:

- H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Don't Care

## PIN DESCRIPTION

TERMINAL		Description
Symbol	I/O	
1G	I	Output Enable Control for 1Y(0:4) Outputs. This output enable is active HIGH. If this pin is Logic HIGH, the 1Y(0:4) clock outputs will follow the input clock (CLK). If this pin is logic LOW, the 1Y(0:4) outputs will drive low independent of the state of CLK.
2G	I	Output Enable Control for 2Y(0:4) Outputs. This output enable is active HIGH. If this pin is Logic HIGH, the 2Y(0:4) clock outputs will follow the input clock (CLK). If this pin is logic LOW, the 2Y(0:4) outputs will drive low independent of the state of CLK.
1Y(0:4)	O	Buffered Output Clocks
2Y(0:4)	O	Buffered Output Clocks
CLK	I	Input Reference Frequency
GND		Ground
V <sub>DD</sub>	PWR	DC Power Supply, 2.3V to 3.6V

## RECOMMENDED OPERATING RANGE

Symbol	Description	Min.	Typ.	Max.	Unit
V <sub>DD</sub>	Internal Power Supply Voltage	2.3	2.5		V
			3.3	3.6	
V <sub>IL</sub>	Input Voltage LOW	V <sub>DD</sub> = 3V to 3.6V		0.8	V
		V <sub>DD</sub> = 2.3V to 2.7V		0.7	
V <sub>IH</sub>	Input Voltage HIGH	V <sub>DD</sub> = 3V to 3.6V		2	V
		V <sub>DD</sub> = 2.3V to 2.7V		1.7	
V <sub>I</sub>	Input Voltage	0		V <sub>DD</sub>	V
I <sub>OH</sub>	Output Current HIGH	V <sub>DD</sub> = 3V to 3.6V		-12	mA
		V <sub>DD</sub> = 2.3V to 2.7V		-6	
I <sub>OL</sub>	Output Current LOW	V <sub>DD</sub> = 3V to 3.6V		12	mA
		V <sub>DD</sub> = 2.3V to 2.7V		6	
T <sub>A</sub>	Ambient Operating Temperature	-40		+85	°C

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max	Unit
V <sub>IK</sub>	Input Voltage	V <sub>DD</sub> = 3V, I <sub>IN</sub> = -18mA			-1.2	V
I <sub>IN</sub>	Input Current	V <sub>I</sub> = 0V or V <sub>DD</sub>			±5	μA
I <sub>DD</sub>	Static Device Current <sup>(1)</sup>	CLK = 0V or V <sub>DD</sub> , I <sub>O</sub> = 0mA, V <sub>DD</sub> = 3.3V			25	μA

**NOTE:**

1. For I<sub>DD</sub> over frequency, see TEST CIRCUIT AND WAVEFORMS.

## DC ELECTRICAL CHARACTERISTICS - V<sub>DD</sub> = 3.3V ± 0.3V

Symbol	Parameter	Test Conditions		Min.	Typ. <sup>(1)</sup>	Max	Unit
V <sub>OH</sub>	HIGH level Output Voltage	V <sub>DD</sub> = Min. to Max.	I <sub>OH</sub> = -100μA	V <sub>DD</sub> - 0.2			V
		V <sub>DD</sub> = 3V	I <sub>OH</sub> = -12mA	2.1			
			I <sub>OH</sub> = -6mA	2.4			
V <sub>OL</sub>	LOW level Output Voltage	V <sub>DD</sub> = Min. to Max.	I <sub>OL</sub> = 100μA			0.2	V
		V <sub>DD</sub> = 3V	I <sub>OL</sub> = 12mA			0.8	
			I <sub>OL</sub> = 6mA			0.55	
I <sub>OH</sub>	HIGH level Output Current	V <sub>DD</sub> = 3V	V <sub>O</sub> = 1V	-28			mA
		V <sub>DD</sub> = 3.3V	V <sub>O</sub> = 1.65V		-36		
		V <sub>DD</sub> = 3.6V	V <sub>O</sub> = 3.135V			-14	
I <sub>OL</sub>	LOW level Output Current	V <sub>DD</sub> = 3V	V <sub>O</sub> = 1.95V	28			mA
		V <sub>DD</sub> = 3.3V	V <sub>O</sub> = 1.65V		36		
		V <sub>DD</sub> = 3.6V	V <sub>O</sub> = 0.4V			14	

**NOTE:**

1. All typical values are at respective nominal V<sub>DD</sub>.

DC ELECTRICAL CHARACTERISTICS -  $V_{DD} = 2.5V \pm 0.2V$

Symbol	Parameter	Test Conditions		Min.	Typ. <sup>(1)</sup>	Max	Unit
V <sub>OH</sub>	HIGH level Output Voltage	V <sub>DD</sub> = Min. to Max.	I <sub>OH</sub> = -100μA	V <sub>DD</sub> - 0.2			V
		V <sub>DD</sub> = 2.3V	I <sub>OH</sub> = -6mA	1.8			
V <sub>OL</sub>	LOW level Output Voltage	V <sub>DD</sub> = Min. to Max.	I <sub>OL</sub> = 100μA			0.2	V
		V <sub>DD</sub> = 2.3V	I <sub>OL</sub> = 6mA			0.55	
I <sub>OH</sub>	HIGH level Output Current	V <sub>DD</sub> = 2.3V	V <sub>O</sub> = 1V	-17			mA
		V <sub>DD</sub> = 2.5V	V <sub>O</sub> = 1.25V		-25		
		V <sub>DD</sub> = 2.7V	V <sub>O</sub> = 2.375V			-10	
I <sub>OL</sub>	LOW level Output Current	V <sub>DD</sub> = 2.3V	V <sub>O</sub> = 1.2V	17			mA
		V <sub>DD</sub> = 2.5V	V <sub>O</sub> = 1.25V		25		
		V <sub>DD</sub> = 2.7V	V <sub>O</sub> = 0.3V			10	

NOTE:

1. All typical values are at respective nominal V<sub>DD</sub>.

TIMING REQUIREMENTS OVER RECOMMENDED RANGE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max	Unit
f <sub>CLK</sub>	Clock Frequency	V <sub>DD</sub> = 3V to 3.6V	0		200	MHz
		V <sub>DD</sub> = 2.3V to 2.7V	0		170	

## SWITCHING CHARACTERISTICS OVER OPERATING RANGE -

$$V_{DD} = 3.3V \pm 0.3V^{(1)}$$

Symbol	Parameter	Test Conditions	Min.	Typ. <sup>(1)</sup>	Max	Unit
t <sub>PLH</sub> t <sub>PHL</sub>	CLK to Yx	f = 0MHz to 200MHz	1.3		2.8	ns
tsk(o) <sup>(2)</sup>	Output Skew, Yx to Yx				100	ps
tsk(p)	Pulse Skew				250	ps
tsk(pp)	Part-to-Part Skew				500	ps
t <sub>R</sub>	Rise Time	V <sub>O</sub> = 0.4V to 2V <sup>(3)</sup>	0.7		2	V/ns
t <sub>F</sub>	Fall Time	V <sub>O</sub> = 2V to 0.4V <sup>(3)</sup>	0.7		2	V/ns
tsu	G before CLK↓	V <sub>(THRESHOLD)</sub> = V <sub>DD</sub> /2	0.1			ns
t <sub>H</sub>	G after CLK↓		0.4			

### NOTES:

1. All typical values are at respective nominal V<sub>DD</sub>.
2. This specification is only valid for equal loading of all outputs.
3. Measured at 100MHz.

## SWITCHING CHARACTERISTICS OVER OPERATING RANGE -

$$V_{DD} = 2.5V \pm 0.2V^{(1)}$$

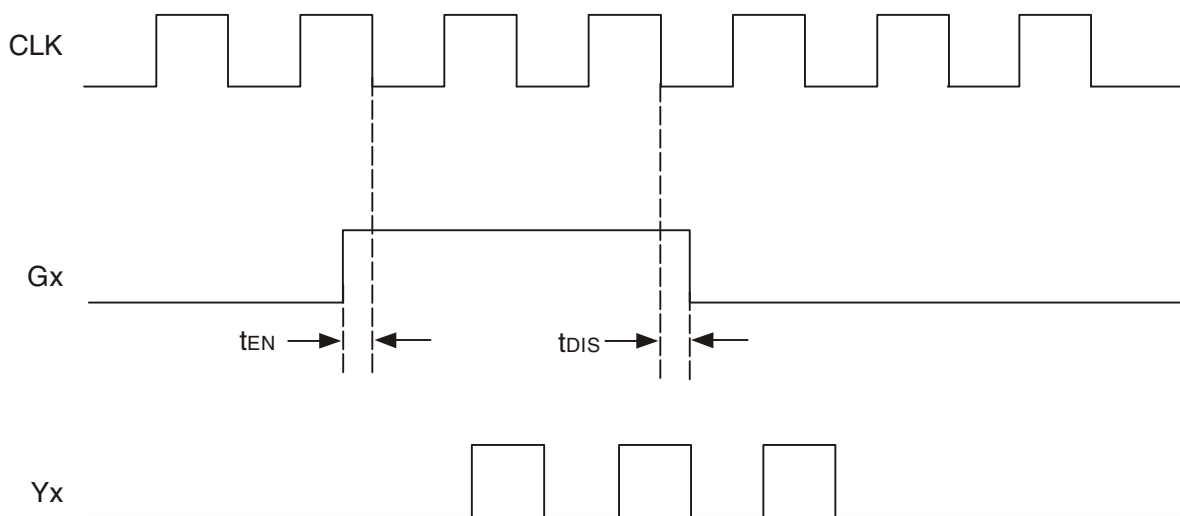
Symbol	Parameter	Test Conditions	Min.	Typ. <sup>(1)</sup>	Max	Unit
t <sub>PLH</sub> t <sub>PHL</sub>	CLK to Yx	f = 0MHz to 170MHz	1.5		3.5	ns
tsk(o) <sup>(2)</sup>	Output Skew, Yx to Yx				100	ps
tsk(p)	Pulse Skew				400	ps
tsk(pp)	Part-to-Part Skew				600	ps
t <sub>R</sub>	Rise Time	V <sub>O</sub> = 0.4V to 1.7V <sup>(3)</sup>	0.5		1.4	V/ns
t <sub>F</sub>	Fall Time	V <sub>O</sub> = 1.7V to 0.4V <sup>(3)</sup>	0.5		1.4	V/ns
tsu	G before CLK↓	V <sub>(THRESHOLD)</sub> = V <sub>DD</sub> /2	0.1			ns
t <sub>H</sub>	G after CLK↓		0.4			

### NOTES:

1. All typical values are at respective nominal V<sub>DD</sub>.
2. This specification is only valid for equal loading of all outputs.
3. Measured at 100MHz.

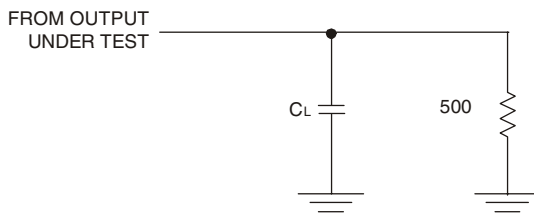
## OUTPUT ENABLE GLITCH SUPPRESSION CIRCUIT

The purpose of the glitch suppression circuitry is to ensure the output enable sequence is synchronized with the clock input such that the output buffer will be enabled on the next full period of the input clock (negative edge triggered by the input clock). The G input must be stable one  $t_{EN}$  - time prior to the falling edge of the CLK for predictable operation.



*G ( $t_{EN}$ ,  $t_{DIS}$ ) Relative to CLK↓*

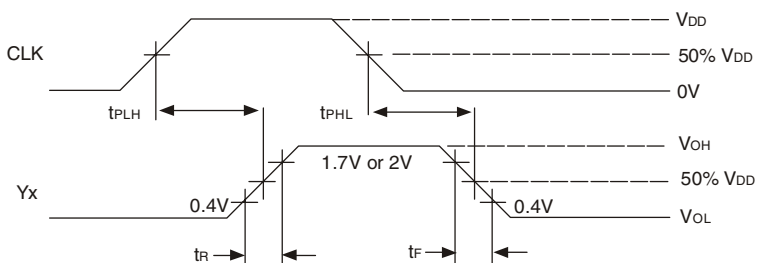
## TEST CIRCUITS AND WAVEFORMS



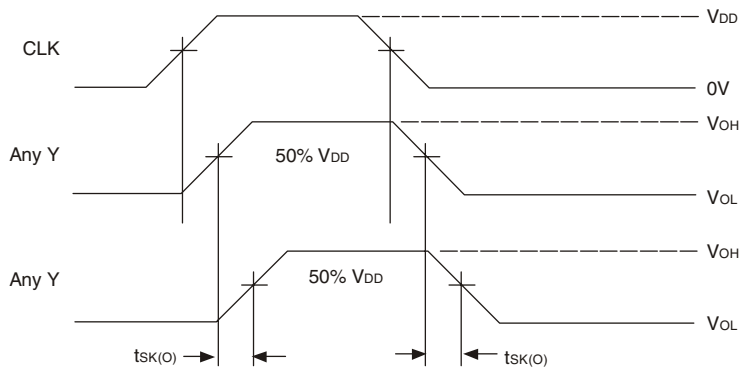
**NOTES:**

1.  $C_L$  includes probe and jig capacitance.
2. All input pulses are supplied by generators having the following characteristics:  
PRR  $\leq$  200MHz;  $Z_0 = 50\Omega$ ;  $t_R < 1.2ns$ ;  $t_F < 1.2ns$ .

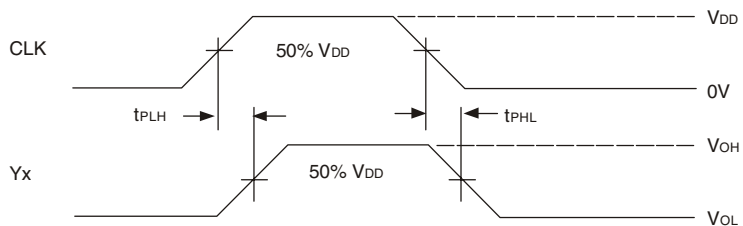
### Test Load Circuit



### Voltage Waveforms Propagation Delay Times



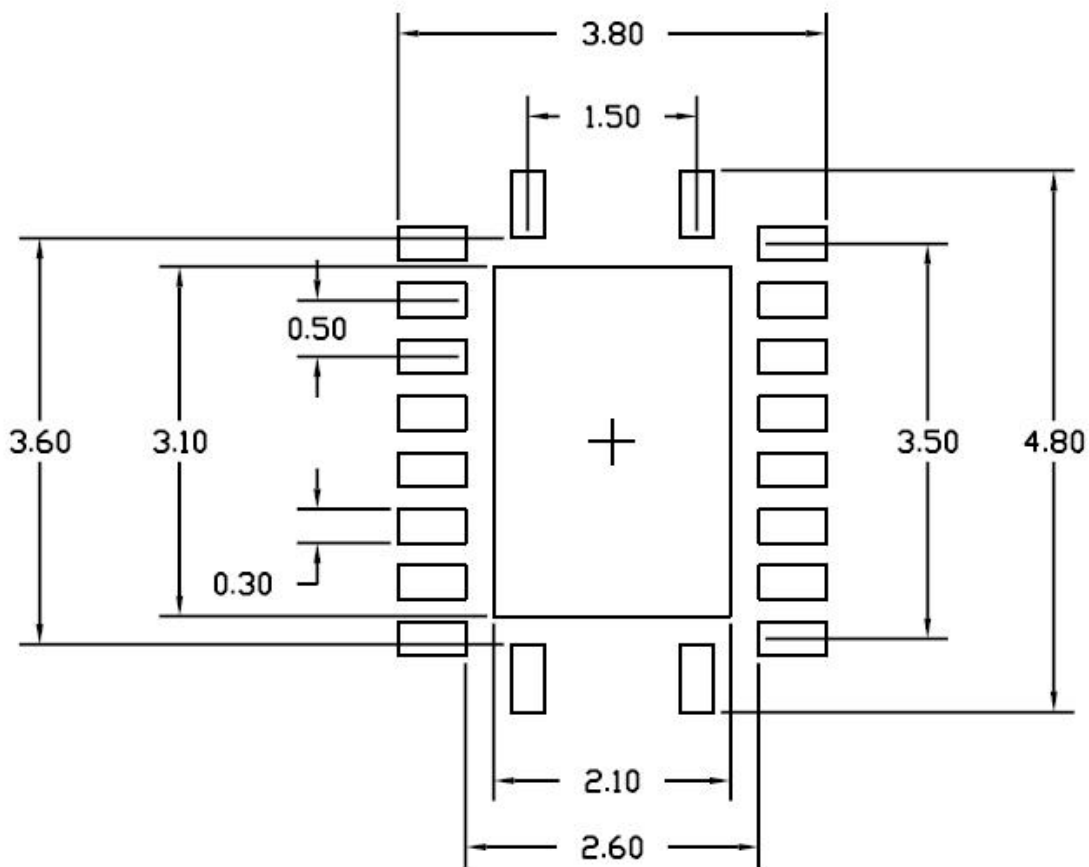
### Output Skew



$$t_{SK(P)} = |t_{PLH} - t_{PHL}|$$

### Pulse Skew

RECOMMENDED LANDING PATTERN



*NR 20 pin*

NOTE: All dimensions are in millimeters.



## ORDERING INFORMATION

5V2310PGGI	Tubes	24-pin TSSOP	-40 to +85°C
5V2310PGGI8	Tape & Reel	24-pin TSSOP	-40 to +85°C
5V2310NRGI	Tubes	20-pin VFQFPN	-40 to +85°C
5V2310NRGI8	Tape & Reel	20-pin VFQFPN	-40 to +85°C



**CORPORATE HEADQUARTERS**  
6024 Silver Creek Valley Road  
San Jose, CA 95138

**for SALES:**  
800-345-7015 or 408-284-8200  
fax: 408-284-2775  
[www.idt.com](http://www.idt.com)

**for Tech Support:**  
[clockhelp@idt.com](mailto:clockhelp@idt.com)